

| | | | | |
|-----------------------------------|--|-----------------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
| | | Examiner Jermele M. Hollington | Art Unit 2829 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-5,307,011 A | 04-1994 | Tani, Mitsuaki | 324/158.1 |
| * | B | US-5,313,156 A | 05-1994 | Klug et al. | 324/158.1 |
| * | C | US-5,319,353 A | 06-1994 | Ohnishi et al. | 340/525 |
| * | D | US-5,742,168 A | 04-1998 | Kiyokawa et al. | 324/754 |
| * | E | US-5,788,084 A | 08-1998 | Onishi et al. | 324/158.1 |
| * | F | US-5,909,657 A | 06-1999 | Onishi et al. | 702/108 |
| * | G | US-6,198,273 B1 | 03-2001 | Onishi et al. | 324/754 |
| * | H | US-6,384,593 B1 | 05-2002 | Kobayashi et al. | 324/765 |
| * | I | US-6,515,470 B2 | 02-2003 | Suzuki et al. | 324/754 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.